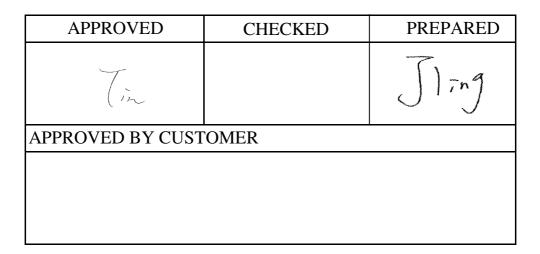
APPROVAL SHEET

:			
:			
:	8.000000	MHz	
:	SMAN-008000-5-D4-00		
:	SMAN-008000-5-D4-00)	
:	1		
:	Feb.10.2023		
	:	 : 8.000000 : 8.000000 : SMAN-008000-5-D4-00 : SMAN-008000-5-D4-00 : 1 : Feb.10.2023 	



AKER TECHNOLOGY CO., LTD.

ADDRESS : NO 11-3, Jianguo Rd., Tanzi Dist., Taichung City 427, Taiwan.

TEL: 886-4-25335978 FAX: 886-4-25336011

Web: www.aker.com.tw

MSL:Level 1 RoHS compliant



Aker Approved	P/N :	SMAN-00	08000-5-D4-00
APPROVED	•	Tin	SHEET : 1 of 10
PREPARED	:	JLING	REV. : 1
			Confidential

Rev.	Date	Reviser	Revise contents
1	2023/2/10	JLING	Initial Released



Aker Approved P	/N :	SMAN-00)8000-5-D4-00
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SMD CRYSTAL OSCILLATOR

1. ELECTRICAL CHARACTERISTICS

Standard atmospheric conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurement and tests are as follow :

Ambient temperature : 25 ± 5 °C

Relative humidity : 40%~70%

If there is any doubt about the results, measurement shall be made within the following limits:

Ambient temperature : 25 ± 3 °C

Relative humidity : 40%~70%

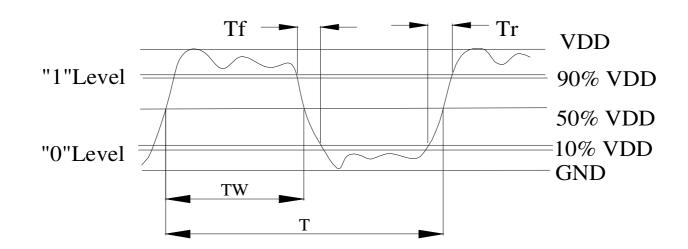
- AKER Model : SMAN-531
- Cutting Mode : AT CUT

			Electrical Spec			
Parameters	Symbol	Min.	Тур.	Max.	Units.	Notes
Nominal Frequency		<u></u>	8.000000)	MHz	
Frequency Stability			±100		ppm	
Supply Voltage	Vcc	1.62	~	3.63	V	
Output Load CMOS	CL			15	pF	
Aging			±3		ppm	First Year
Enable Control			Yes			Pad 1
Operating Temperature		-40	25	105	°C	
Storage Temperature Range		-55	~	125	°C	
Output Voltage High	VoH	90%Vdd			V	
Output Voltage Low	VoL			10%Vdd	V	
Input Current	Icc			7	mA	
Standby Current	Ist		l	20	μA	
Rise Time	Tr			10	ns	10%~90%VDD Level
Fall Time	Tf			10	ns	90%~10%V _{DD} Level
Symmetry (Duty ratio)	TH/T	45	~	55	%	
Start-up Time	Tosc			10	ms	
Enable Voltage High	Vhi	70%Vdd			V	
Disable Voltage Low	Vlo			30%Vdd	V	
Output Enable Delay Time	T on			10	ms	
Output Disable Delay Time	T off			200	ns	
Please kindly be noted that AKER	DO NOT g	uarantee p	arts qualit	y which in	volves	human security application.

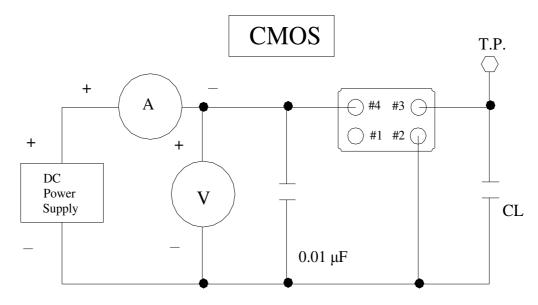


Aker Approved P	/N :	SMAN-00	SMAN-008000-5-D4-00		
APPROVED	:	Tin	SHEET : 3 of 10		
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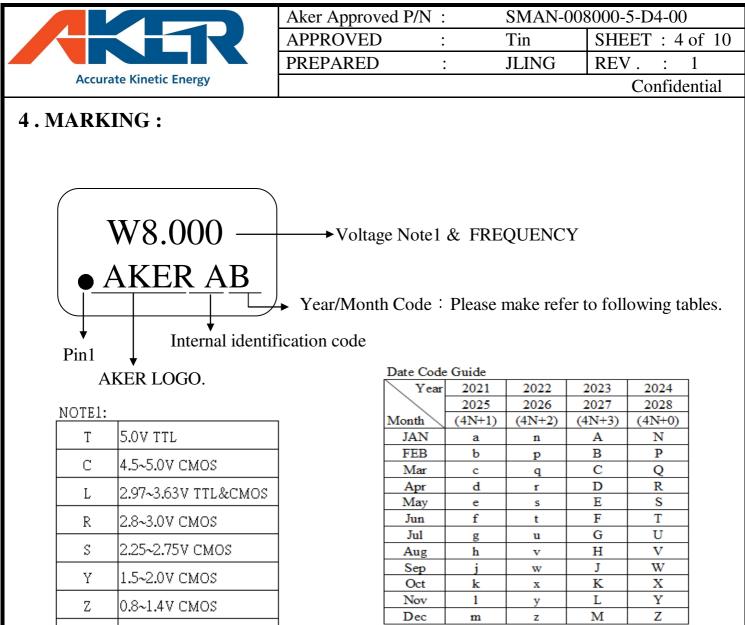
2. C - MOS LOAD OUTPUT WAVEFORM



3.C-MOS LOAD TEST CIRCUIT



***Because SMA series has no by pass capacitor. So,we recommend our customer to use capacitor $0.01 \ \mu F$ in join Vcc and GND.



A cycle every four years

5. DIMENSION :

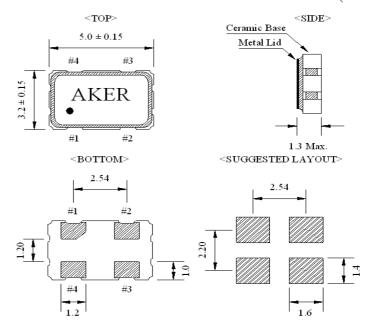
W

Enable / Disable Function

E/D (#1)	OUTPUT(#3)
HIGH (Open)	Operating
LOW	High impedance

Voltage Range CMOS

PIN FUNCTION					
#1:Enable / Disable Cont	rol				
#2 : GND					
#3 : OUTPUT					
#4 : VDD					

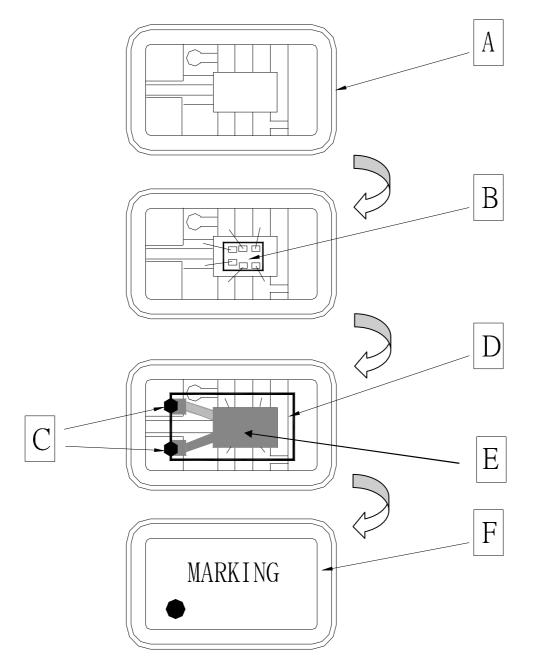


(UNIT:mm)



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6 . STRUCTURE ILLUSTRATION

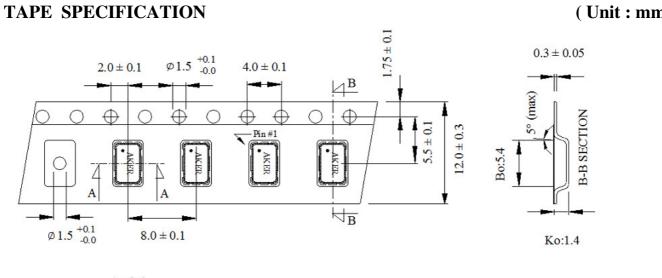


	COMPONENTS	MATERIALS	CO	MPONENTS	MATERIALS
A	Base (Package)	Ceramic (Al2O3)+Kovar (Fe/Co/Ni)	D	Crystal blank	SiO2
В	IC chip		E	Electrode	Cr / Ag
С	Conductive adhesive	Ag / Silicon resin	F	Lid	Fe/Co/Ni

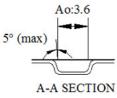


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7. PACKING :

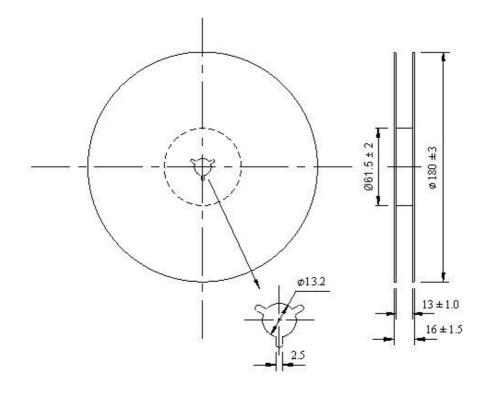


Feeding

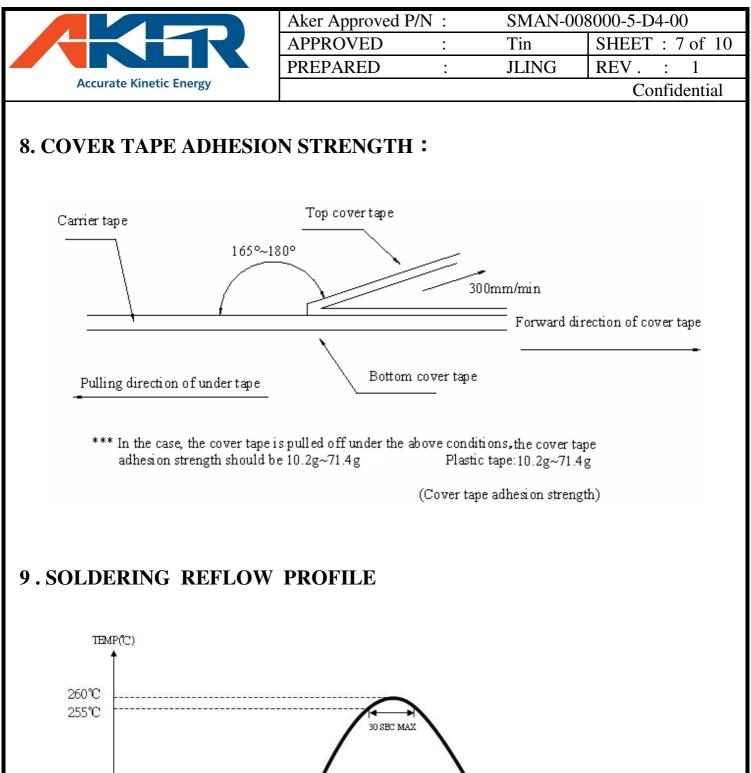


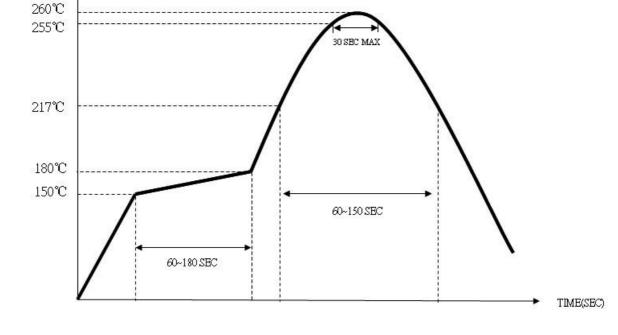
OUTLINE DIMENSION

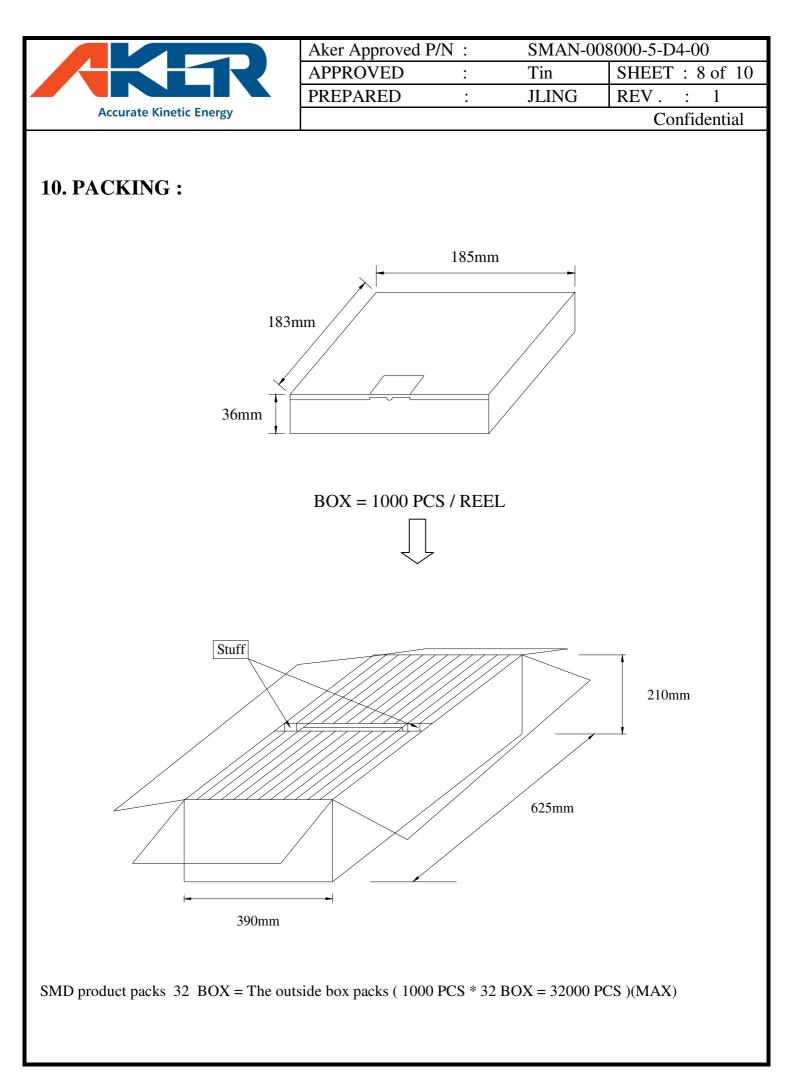
(Unit:mm)



(Unit:mm)









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APPROVED	:	Tin	SHEET : 9 of 10
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11. MECHANICAL PERFORMANCE					
TEST ITEMS	TEST METHODS AND TEST CONDITION	PERFORMANCE			
11.1 Drop Test	The specimen is measured for its frequency before the test. It is then dropped from a hight of 75 cm or more as a free fall object onto a hard wooden plate of 30mm or more in thickness. (in accordance with JIS-C0044)				
11.2 Vibration Test	The specimen is measured for its frequency before the test. Most them into X,Y and Z axes, respectively, for the vibration test. Vibration condition: Frequency range ; $20 \sim 2000$ HZ Peak to peak amplitude : 1.52 mm Peak acceleration : 20 G Sweep time : 20 minute / axis Pendicular total test time : 4 hours (in accordance with MIL-STD-883F : 2007.3)	To satisfy the electrical performance .			
11.3 Resistance to Soldering Test	The specimen is measured for its frequency before the test. Place the specimen on the belt of the converynace and let it pass through the reflow with the presetted temperature condition. After passing twice the reflow place, the specimen under the referee condition for -~2 hours and then measure its electrical performance. Temperature Condition of IR Simulation: The temperature range of the preheated section is setted at $150 \sim 180^{\circ}$ C for $60 \sim 120$ sec. For the next section the temperature range is setted at $217 \sim 260^{\circ}$ C for $45 \sim 90$ sec. and within this time range the specimen should be able to sustain at the peak temperature, $260 + /-3^{\circ}$ C , for 10 sec long. (in accordance with JESD22-B106-B)				
11.4 Fine Leak Test	Place the specimen in a pressurized container and pressurize it with the detection gas (mixed gas consisting of 95% or more helium) for at least 2 hours. Complete the measurement of the concentration of helium within 30 min after taking it out from the pressurized container.	Less than 1.0 * 10 ^{- 8} atm .c.c. / sec, Helium			
	(in accordance with MIL-STD-883F : 1014.11) The referee condition. Temperature 25 ± 2 °C Humidity $44 \sim 55$ % Pressure $86 \sim 106$ kPa (in accordance with MIL-STD-883E : 1014.9)				



Aker Approved F	P/N :	SMAN-0	08000-5-D4-00
APPROVED	:	Tin	SHEET : 10 of 10
PREPARED	:	JLING	REV. : 1
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12. CLIMATIC RESISTANCE

TEST ITEMS	TEST METHODS AND TEST CONDITION	PERFORMANCE				
12.1 Low Temp Exposure Test	The specimen is measured for its frequency before the test . Place the specimen in the chamber and kept it at the temperature of $-40 \pm 3^{\circ}$ C for 168 ± 6 hours . Take the specimen out of the chamber and measure itselectrical performance after leaving $1 \sim 2$ hours under the referee condition. (in accordance with JIS-C0020)					
12.2 Aging Test	The specimen is measured for its frequency before the test . Place the specimen in the testing chamber and keep it at the temperature of $+ 125 \pm 3^{\circ}$ C for 720 ± 48 hours. And then take the specimen out of the chamber and measure its electrical performance after leaving for 1 \sim 2 hours under the referee condition . (in accordance with JIS-C0021)	To satisfy the electrical performance .				
12.3 High Temperature & High Humidty	The specimen is measured for its frequency before the test . Place the specimen in the testing chamber and kept it at the temperature of $+85 \pm 5$ °C and humidity of 85 ± 5 % for 168 ± 6 hours.and then take the specimen out and measure its electrical performance after leaving for $1 \sim 2$ hours under the referee condition. (in accordance with MIL-STD-883F : 1004.7)					
12.4 Temperature Cycle Test	The specimen is measured for its frequency before the test . Subject the specimen to the 100 cycles of temperature ranges stated below . High temp . + 125 ± 3 °C (15± 3 min). $2\sim 3 \min$ $2\sim 3 \min$. Low temp55 ± 3 °C (15± 3 min). Measure its electrical performance after leaving it for 1 ~ 2 hours under the referee condition . (in accordance with MIL-STD-883F : 1010.8)					